Flexible ultraviolet photodetector based on single crystalline MoO$_3$ nanosheet

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Fig. S1 Schematic diagram of the horizontal physical vapor deposition system

Fig. S2 Schematic diagram of the flexible metal-semiconductor-metal structure UVPD based on MoO$_3$/PET
Fig. S3 Thickness of the MoO$_3$ nanosheet using for the MSM UVPD measured by Bruker Dektak XT profilometer, which is found to be 78.4 nm.